

<b>Notice of References Cited</b>	Application/Control No. 09/967,167	Applicant(s)/Patent Under Reexamination CHU ET AL.	
	Examiner Laurie Ries	Art Unit 2176	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,969,717	10-1999	Ikemoto, Hiroyuki	715/762
	B	US-6,037,939	03-2000	Kashiwagi et al.	715/798
	C	US-5,895,477	04-1999	Orr et al.	715/517
	D	US-5,583,983	12-1996	Schmitter, Robert L.	717/138
	E	US-6,353,448	03-2002	Scarborough et al.	715/744
	F	US-5,956,738	09-1999	Shirakawa, Takahisa	715/517
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"UIML Reference Manual", Harmonia, Inc, December 1997, downloaded from <a href="http://www.uiml.org/specs/docs/uiml_v10_ref.PDF">http://www.uiml.org/specs/docs/uiml_v10_ref.PDF</a> , pp. 1-132.
	V	"User Interface Markup Language (UIML) Draft Specification", Harmonia, Inc, Version 7, January 2000, downloaded from <a href="http://www.uiml.org/specs/docs/uiml20-17Jan00.pdf">http://www.uiml.org/specs/docs/uiml20-17Jan00.pdf</a> , pp. 1-64.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.